

Fig. 1

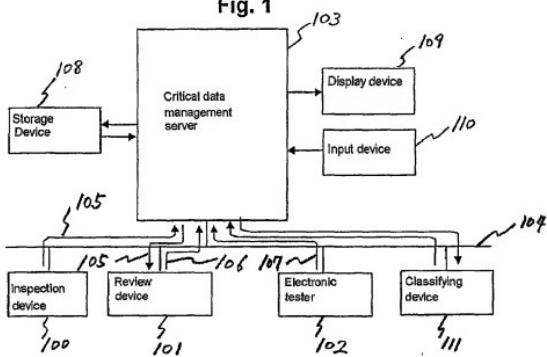


Fig. 3

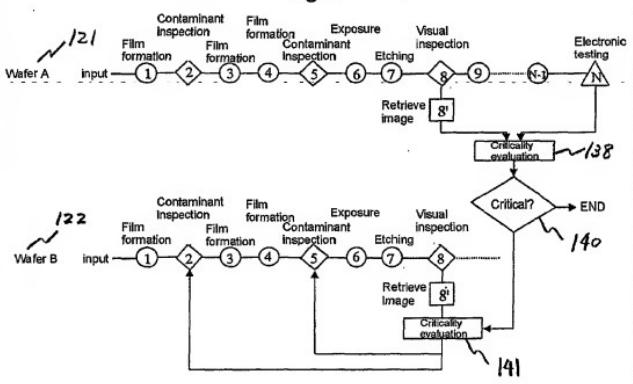


Fig. 2

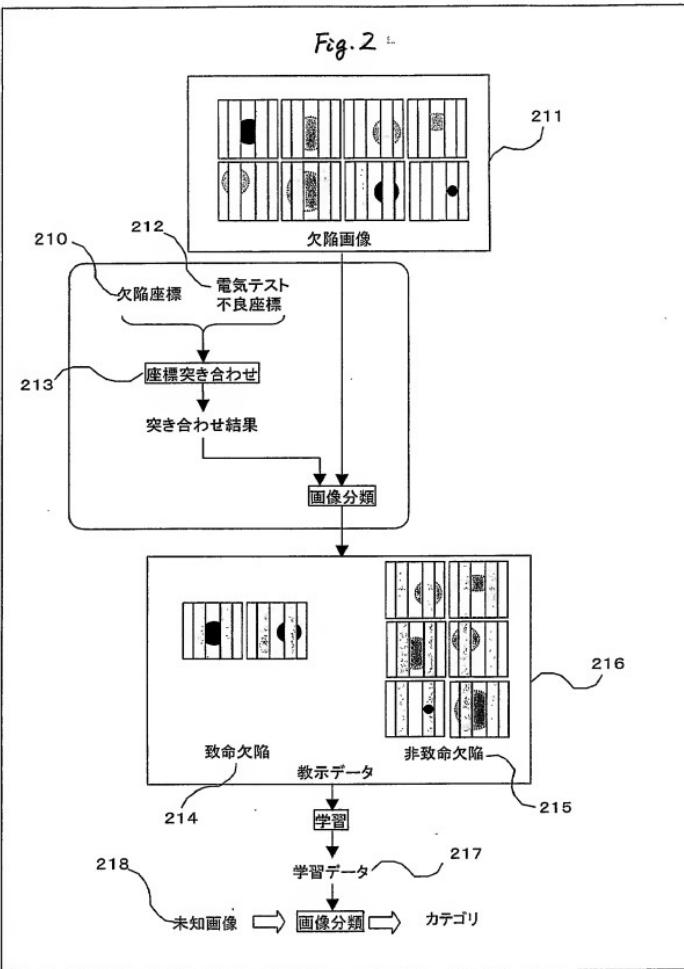


Fig. 4

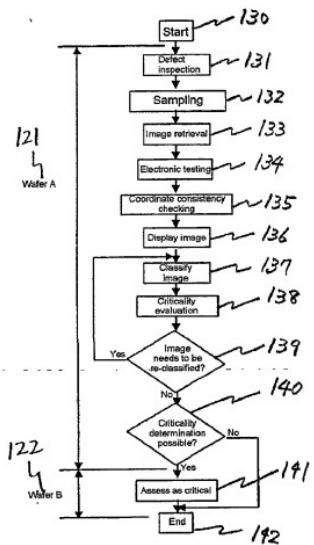


Fig. 5

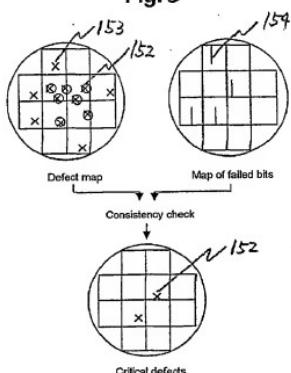


Fig. 6

Defect number	Chip coordinates	Defect coordinates	Sampling flag	Image name	Test result
1	(2,0)	($\Delta X_1, \Delta Y_1$)	0		G
2	(0,1)	($\Delta X_2, \Delta Y_2$)	0		G
3	(1,1)	($\Delta X_3, \Delta Y_3$)	1	image3	N
4	(2,1)	($\Delta X_4, \Delta Y_4$)	1	image4	N
5	(0,2)	($\Delta X_5, \Delta Y_5$)	0		G
6	(1,2)	($\Delta X_6, \Delta Y_6$)	1	image6	G
7	(1,2)	($\Delta X_7, \Delta Y_7$)	1	image7	G
8	(1,2)	($\Delta X_8, \Delta Y_8$)	1	image8	G
9	(2,2)	($\Delta X_9, \Delta Y_9$)	1	image9	N
10	(2,2)	($\Delta X_{10}, \Delta Y_{10}$)	1	image10	N
11	(3,2)	($\Delta X_{11}, \Delta Y_{11}$)	0		G
12	(1,3)	($\Delta X_{12}, \Delta Y_{12}$)	0		N

Fig. 7

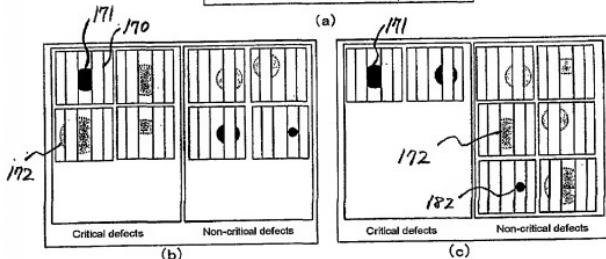
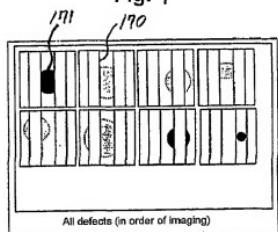


Fig. 9

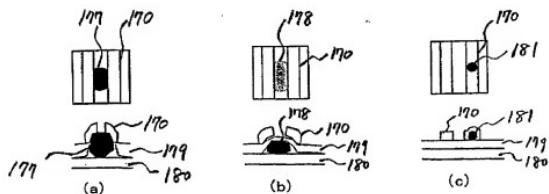


Fig. 8

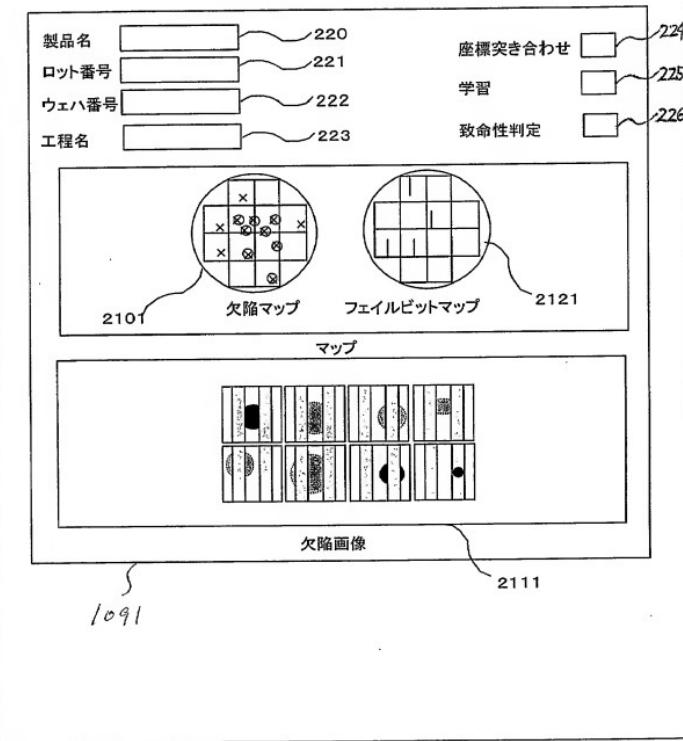


Fig.10

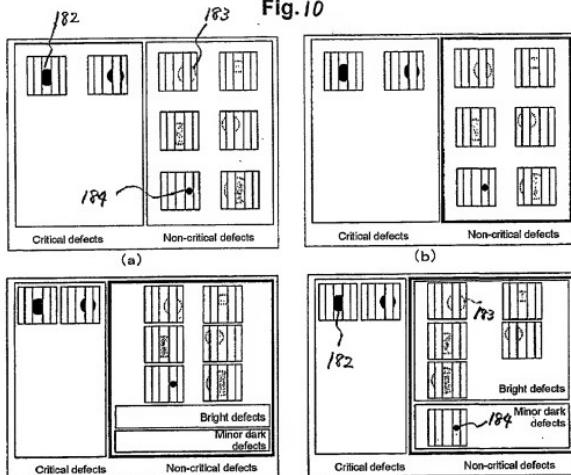


Fig.11

Defect number	Chip coordinates	Defect coordinates	Sampling flag	Image name	Test result	Image classification
1	(2,0)	(ΔX1, ΔY1)	0		G	G
2	(0,1)	(ΔX2, ΔY2)	0		G	G
3	(1,1)	(ΔX3, ΔY3)	1	image3	N	N
4	(2,1)	(ΔX4, ΔY4)	1	image4	N	N
5	(0,2)	(ΔX5, ΔY5)	0		G	G
6	(1,2)	(ΔX6, ΔY6)	1	image6	G	G
7	(1,2)	(ΔX7, ΔY7)	1	image7	G	G
8	(1,2)	(ΔX8, ΔY8)	1	image8	G	G
9	(2,2)	(ΔX9, ΔY9)	(0)	image9	N	N
10	(2,2)	(ΔX10, ΔY10)	1	image10	N	N
11	(3,2)	(ΔX11, ΔY11)	0		G	G
12	(1,3)	(ΔX12, ΔY12)	0		N	N

Fig. 12

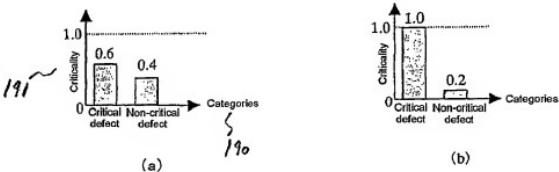


Fig. 13

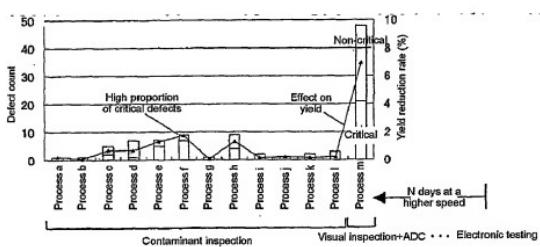


Fig. 14

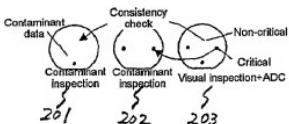


Fig. 15.

